



Fringe Projection Profilometry for Fast and Accurate 3D Surface Analysis

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Message from the Guest Editors

The outstanding features of Fringe projection profilometry (FPP) rely on its ability to provide automatic, accurate, high-resolution, full-field 3D surface information. Even if several approaches have been proposed in the last years, 3D surface analysis in real scenarios is still affected by many problems, due to a variety of global illumination effects (high reflectivity, inter-reflections, surface scattering, etc.). FPP is still an active research field for the scientific community.

Keywords

Deadline for manuscript
submissions:

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- Fringe projection profilometry
- Phase shifting
- Structured light sensing
- 3D shape measurement
- 3D imaging
- Phase unwrapping
- 3D surface analysis
- Camera calibration
- Optical metrology



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Message from the Editor-in-Chief

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